Abstracts

A New Measurement System for Oscillator Noise Characterization

A.N. Riddle and R.J. Trew. "A New Measurement System for Oscillator Noise Characterization." 1987 MTT-S International Microwave Symposium Digest 87.1 (1987 Vol. I [MWSYM]): 509-512.

The prediction of oscillator noise has been one of the more difficult problems in circuit analysis. A new system for measuring modulation (amplitude or phase) transfer and upconversion is presented which allows insight into the causes of oscillator noise. This system can measure modulation at less than -50dbc and accurately predict the oscillator noise spectrum.

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